Application/Control No. Applicant(s)/Patent Under Reexamination 10/789,963 SEN ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 Tae H. Yoon 1714 **U.S. PATENT DOCUMENTS Document Number** Date Name Classification Country Code-Number-Kind Code MM-YYYY US-7,086,732 08-2006 Kasperchik et al. 347/105 Α US-В US-С US-D US-Ε US-F US-G US-Н US-1 US-US-Κ US-US-М **FOREIGN PATENT DOCUMENTS Document Number** Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Ρ Q R s Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U

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